

# N-Channel 650 V (D-S)MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	650					
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	2.1				
Q <sub>g</sub> (Max.) (nC)	48					
Q <sub>gs</sub> (nC)	12					
Q <sub>gd</sub> (nC)	19					
Configuration	Single					

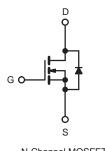
### **FEATURES**

• Low Gate Charge Q<sub>g</sub> Results in Simple Drive Requirement



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> $T_C = 25 \text{ °C}$ , unless otherwise noted								
PARAMETER			SYMBOL	LIMIT	UNIT			
Drain-Source Voltage			V <sub>DS</sub>	650	V			
Gate-Source Voltage			V <sub>GS</sub>	± 30	v			
Continuous Drain Current <sup>e</sup>	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	I <sub>D</sub>	4.5				
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		4.2	A			
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	18				
Linear Derating Factor				0.48	W/°C			
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	325	mJ			
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	4	А			
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	6	mJ			
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	60	W			
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	2.8	V/ns			
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature) <sup>d</sup>	for	10 s		300				
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in			
				1.1	N·m			

### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T<sub>J</sub> = 25 °C, L = 24 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.2 A (see fig. 12). c. I<sub>SD</sub>  $\leq$  3.2 A, dl/dt  $\leq$  90 A/µs, V<sub>DD</sub>  $\leq$  V<sub>DS</sub>, T<sub>J</sub>  $\leq$  150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RA	TINGS							
PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65						
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 2.1				°C/W		
<b>SPECIFICATIONS</b> T <sub>J</sub> = 25 °C,	unless other	vise noted						
PARAMETER	SYMBOL	1		ONS	MIN.	TYP.	MAX.	UNIT
Static		1						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 2	50 µA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>		Reference to 25 °C, $I_D = 1 \text{ mA}^d$			670	-	mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}$			-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	+	= 650 V, V <sub>GS</sub>		-	-	25	
		$V_{DS} = 520 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$			-	-	250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub>	= 3.1 A <sup>b</sup>	-	2.1	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> :	= 50 V, I <sub>D</sub> =	3.1 A	3.9	-	-	S
Dynamic		1						
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,		-	1417	-	1
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0.V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	177	-	1	
Reverse Transfer Capacitance	C <sub>rss</sub>			fig. 5	-	7.0	-	1
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 1.0	V, f = 1.0 MHz	-	1912	-	pF
			V <sub>DS</sub> = 520	0 V, f = 1.0 MHz	-	48	-	1
Effective Output Capacitance	C <sub>oss</sub> eff.	]	$V_{DS} = 0$	) V to 520 V <sup>c</sup>	-	84	-	
Total Gate Charge	Qg		I <sub>D</sub> = 3.2 A, V <sub>DS</sub> = 400 V	-	-	48	nC	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	12		
Gate-Drain Charge	Q <sub>gd</sub>	-	see fig. 6 and 13 <sup>b</sup>		-	-		19
Turn-On Delay Time	t <sub>d(on)</sub>				-	14	-	
Rise Time	tr	$\begin{split} V_{DD} &= 325 \ V, \ I_D = 3.2 \ A \\ R_G &= 9.1 \ \Omega, \ R_D = 62 \ \Omega, \\ & see \ fig. \ 10^b \end{split}$		-	20	-	- ns	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	34	-		
Fall Time	t <sub>f</sub>			-	18	-		
Drain-Source Body Diode Characteristic	cs	•						
Continuous Source-Drain Diode Current	١ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode			-	-	4	- A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				-	-	21	
Body Diode Voltage	V <sub>SD</sub>	$T_{J} = 25 \text{ °C}, I_{S} = 3.2 \text{ A}, V_{GS} = 0 \text{ V}^{b}$			-	-	1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			-	493	739	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 3.2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}^b$			-	2.1	3.2	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )						L <sub>D</sub> )

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

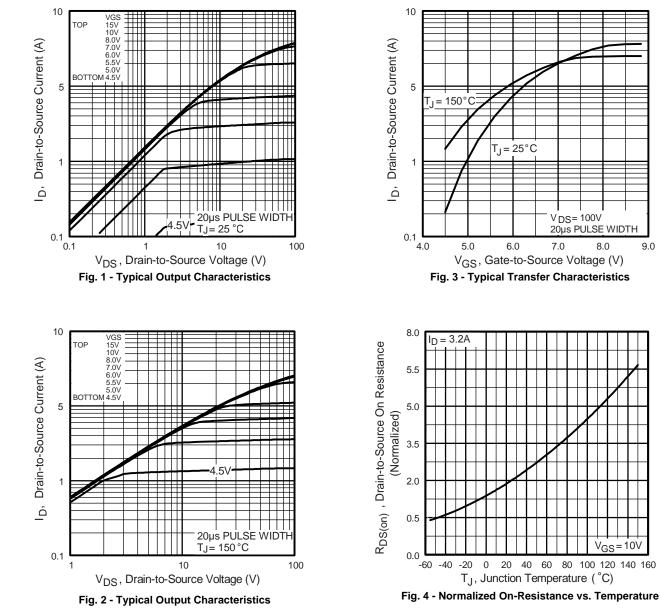
b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.

c.  $C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ .

d. t = 60 s, f = 60 Hz.

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9.0



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

# VBL165R04

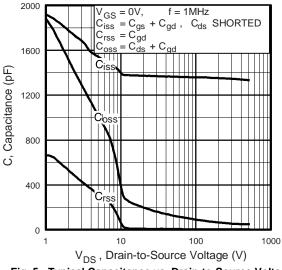


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

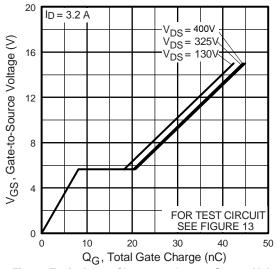
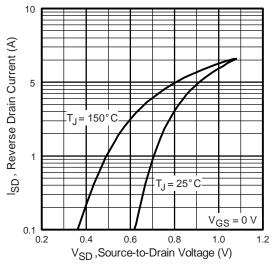


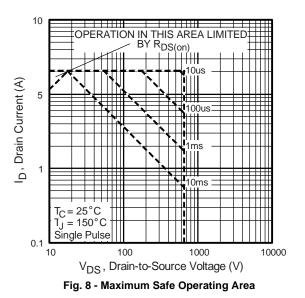
Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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Fig. 7 - Typical Source-Drain Diode Forward Voltage



## **VBL165R04**



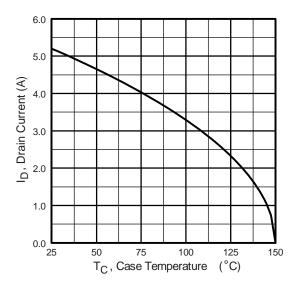


Fig. 9 - Maximum Drain Current vs. Case Temperature

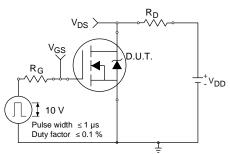


Fig. 10a - Switching Time Test Circuit

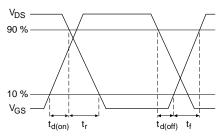
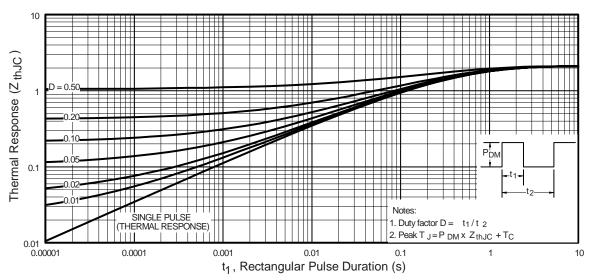


Fig. 10b - Switching Time Waveforms





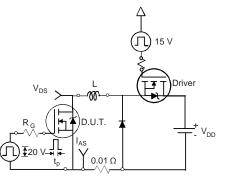
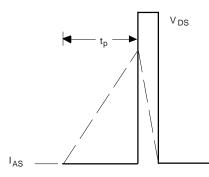
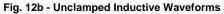


Fig. 12a - Unclamped Inductive Test Circuit





### **VBL165R04**



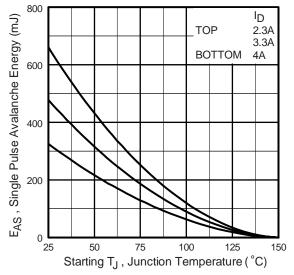


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

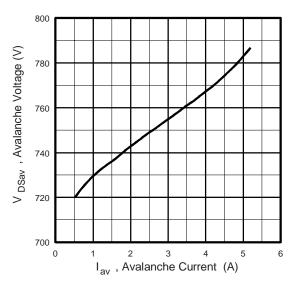


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

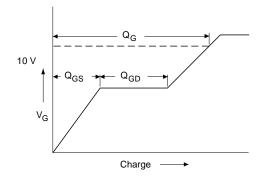


Fig. 13a - Basic Gate Charge Waveform

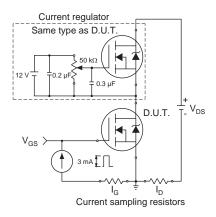
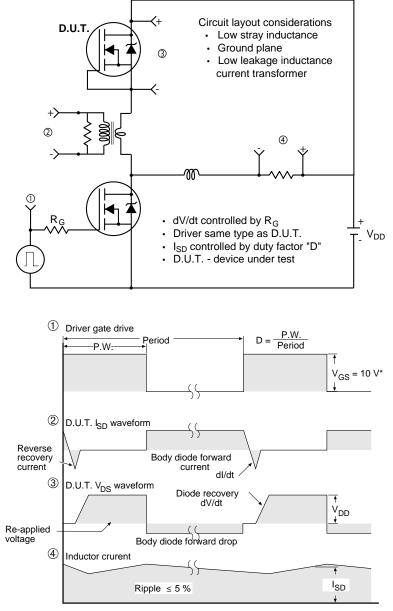


Fig. 13b - Gate Charge Test Circuit





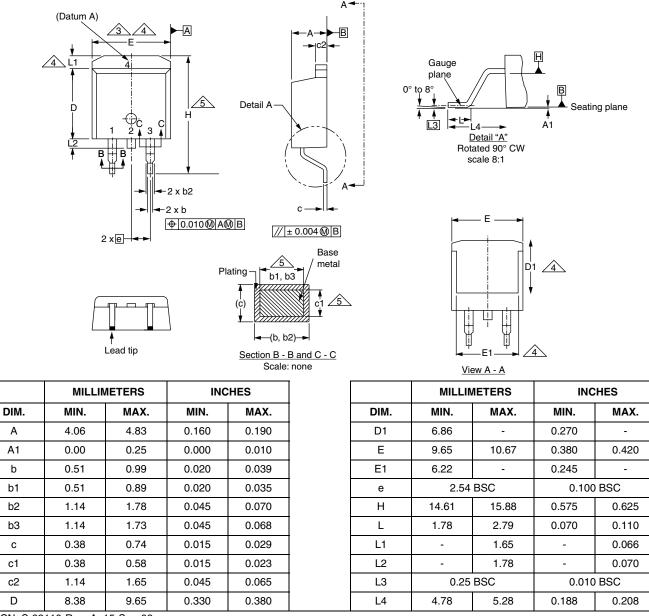
### Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS}$  = 5 V for logic level devices

Fig. 14 - For N-Channel



### **TO-263AB (HIGH VOLTAGE)**



ECN: S-82110-Rev. A, 15-Sep-08 DWG: 5970

#### Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.

- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



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